

# Interpretation of North Pacific Variability as a Short and Long Memory Process

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overheads for talk available at

<http://staff.washington.edu/dbp/talks.html>

joint work with Jim Overland & Hal Mofjeld (PMEL/NOAA)  
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# Introduction

- goal: investigate nature of interdecadal variability in climate time series
- shortness of series poses major difficulties
- one approach: fit & compare various models
  - oscillator
  - nonlinear dynamics (chaos)
  - stochastic
- models have different implications (e.g., nature of regime shifts)
- will investigate influence of choice of stochastic models on representing North Pacific atmospheric data
  - short vs. long memory stochastic models
  - two different atmospheric data sets
    - \* Fig. 1: average (Nov–Mar) Aleutian low sea level pressure field (North Pacific index (NPI))
    - \* Fig. 2: temperature record at Sitka, Alaska

## Overview of Remainder of Talk

- describe short & long memory stochastic models
- discuss maximum likelihood (ML) estimation of model parameters
- look at fitted models for NPI & Sitka
- discuss use of goodness of fit tests to assess models (will find that both models fit equally well)
- discuss how well we can hope to discriminate between short & long memory models
- look at implications of short & long memory models with regard to regime shifts
- consider interpretation of long memory models
- state conclusions

## Short & Long Memory Models

- will consider two Gaussian stationary models for data
  - first order autoregressive process (AR(1))
  - fractionally differenced (FD) process
- both processes fully specified by 3 parameters (and hence both are equally simple)
  1. process mean
  2. parameter that controls process variance
  3. parameter controlling shape of both
    - autocovariance sequence (ACVS) and
    - spectral density function (SDF)
- essential difference between processes
  - AR(1) ACVS dies down quickly (exponentially), so process said to have ‘short memory’
  - FD ACVS dies down slowly (hyperbolically), so process said to have ‘long memory’ (LM)

## Short Memory Stochastic Model

- regard data as realization of portion  $X_0, X_1, \dots, X_{N-1}$  of stationary Gaussian AR(1) process:

$$X_t - \mu_X = \phi(X_{t-1} - \mu_X) + \epsilon_t = \sum_{k=0}^{\infty} \phi^k \epsilon_{t-k}$$

where

1.  $\mu_X = E\{X_t\}$  is process mean
2.  $\epsilon_t$  is white noise with mean zero and variance  $\sigma_\epsilon^2$
3.  $|\phi| < 1$  (if  $\phi = 0$ , then  $X_t$  is white noise)

- ACVS and SDF given by

$$s_{X,\tau} \equiv \text{cov}\{X_t, X_{t+\tau}\} = \frac{\sigma_\epsilon^2 \phi^{|\tau|}}{1 - \phi^2} \quad \& \quad S_X(f) = \frac{\sigma_\epsilon^2}{1 + \phi^2 - 2\phi \cos(2\pi f)},$$

where  $\tau$  is an integer &  $|f| \leq \frac{1}{2}$

- related to discretized 1st order differential equation (has single damping constant (related to  $\phi$ ))
- can define measure of decorrelation (or integral time scale):

$$\tau_D \equiv 1 + 2 \sum_{\tau=1}^{\infty} \frac{s_{X,\tau}}{s_{X,0}} = \frac{1 + \phi}{1 - \phi};$$

i.e., subseries  $X_{n[\tau_D]}$ ,  $n = \dots, -1, 0, 1, \dots$  is close to white noise

## Long Memory Stochastic Model

- regard data as realization of portion  $Y_0, Y_1, \dots, Y_{N-1}$  of stationary Gaussian FD process:

$$\begin{aligned} Y_t - \mu_Y &= \sum_{k=0}^{\infty} \frac{\Gamma(1 + \delta)}{\Gamma(k + 1)\Gamma(1 + \delta - k)} (-1)^k (Y_{t-k} - \mu_Y) \\ &= \sum_{k=0}^{\infty} \frac{\Gamma(1 - \delta)}{\Gamma(k + 1)\Gamma(1 - \delta - k)} (-1)^k \varepsilon_{t-k} \end{aligned}$$

where

1.  $\mu_Y = E\{Y_t\}$  is process mean
  2.  $\varepsilon_t$  is white noise with mean zero and variance  $\sigma_\varepsilon^2$
  3.  $|\delta| < \frac{1}{2}$  (if  $\delta = 0$ ,  $Y_t$  is white noise; LM if  $\delta > 0$ )
- ACVS and SDF given by

$$s_{Y,\tau} = \frac{\sigma_\varepsilon^2 \sin(\pi\delta)\Gamma(1 - 2\delta)\Gamma(\tau + \delta)}{\pi\Gamma(\tau + 1 - \delta)} \quad \& \quad S_Y(f) = \frac{\sigma_\varepsilon^2}{|2 \sin(\pi f)|^{2\delta}}$$

- for  $\tau \geq 1$  and approximately for large  $\tau$  & small  $f$ ,

$$s_{Y,\tau} = s_{Y,\tau-1} \frac{\tau + \delta - 1}{\tau - \delta} \propto |\tau|^{2\delta-1} \quad \text{and} \quad S_Y(f) \propto \frac{1}{|f|^{2\delta}}$$

- related to aggregation of 1st order differential equation involving many different damping constants
- integral time scale  $\tau_D$  is infinite

## Estimation of Model Parameters: I

- AR(1) process  $X_t$  parameterized by  $\mu_X$ ,  $\phi$  &  $\sigma_\varepsilon^2$
- FD process  $Y_t$  parameterized by  $\mu_Y$ ,  $\delta$  &  $\sigma_\varepsilon^2$
- given data that can be regarded as realization of  $X_0, \dots, X_{N-1}$  or  $Y_0, \dots, Y_{N-1}$ , can estimate process mean via sample means:

$$\hat{\mu}_X = \frac{1}{N} \sum_{t=0}^{N-1} X_t \quad \text{and} \quad \hat{\mu}_Y = \frac{1}{N} \sum_{t=0}^{N-1} Y_t$$

- can form recentered series:

$$\widetilde{X}_t \equiv X_t - \hat{\mu}_X \quad \text{and} \quad \widetilde{Y}_t \equiv Y_t - \hat{\mu}_Y$$

- regard  $\widetilde{X}_t$  &  $\widetilde{Y}_t$  as zero mean AR(1) & FD processes
- can use to estimate  $\phi$  &  $\sigma_\varepsilon^2$  or  $\delta$  &  $\sigma_\varepsilon^2$  via maximum likelihood (ML) method
- large sample theory on ML estimators says
  - $\hat{\phi}$  &  $\hat{\sigma}_\varepsilon^2$  are approximately normally distributed with means  $\phi$  &  $\sigma_\varepsilon^2$  and variances  $\frac{1-\phi^2}{N}$  &  $\frac{\sigma_\varepsilon^4}{2N}$
  - $\hat{\delta}$  &  $\hat{\sigma}_\varepsilon^2$  are approximately normally distributed with means  $\delta$  &  $\sigma_\varepsilon^2$  and variances  $\frac{6}{\pi^2 N}$  &  $\frac{\sigma_\varepsilon^4}{2N}$
- Monte Carlo experiments: above valid for  $N \geq 100$

## Estimation of Model Parameters: II

- can use ML theory to form 95% confidence intervals (CIs) for unknown parameters
- can adjust ML procedure to handle time series with missing values (no need to use interpolation)
- can form residuals  $\hat{\epsilon}_t$  and  $\hat{\epsilon}_t$
- can use residuals to test adequacy of model (if adequate, residuals should resemble white noise)



## Fitted Models for NPI and Sitka

- Tab. 1: parameter estimates & CIs for NPI & Sitka
  - AR(1) & FD models both significantly different from white noise (i.e.,  $\phi \neq 0$  and  $\delta \neq 0$ )
  - $\hat{\phi}$ 's similar for NPI & Sitka (as are  $\hat{\delta}$ 's)
  - interpolation increases estimated  $\hat{\phi}$  &  $\hat{\delta}$  for Sitka
- Fig. 3: estimated autocorrelation sequence (ACS) and estimated SDF (periodogram) for NPI, i.e.,

$$\hat{\rho}_\tau \equiv \frac{\hat{s}_{X,\tau}}{\hat{s}_{X,0}} = \frac{\sum_{t=0}^{N-\tau-1} \widetilde{X}_t \widetilde{X}_{t+\tau}}{\sum_{t=0}^{N-1} \widetilde{X}_t^2} \quad \text{and} \quad \hat{S}(f_k) \equiv \frac{1}{N} \left| \sum_{t=0}^{N-1} \widetilde{X}_t e^{-i2\pi f_k t} \right|^2,$$

along with ACSs and SDFs from fitted models

- qualitatively, both models seems reasonable (arguably FD ACS better match to  $\hat{\rho}_\tau$  than AR(1))
- get similar results for Sitka
- can use goodness of fit tests for quantitative assessment of models

## Goodness of Fit Tests: I

1. compare fitted SDF to periodogram:

$$T_1 \equiv \frac{NA}{4\pi B^2}, \text{ where } A \equiv \sum_{k=1}^{\lfloor \frac{N-1}{2} \rfloor} \left( \frac{\hat{S}(f_k)}{S(f_k; \hat{\theta})} \right)^2; \quad B \equiv \sum_{k=1}^{\lfloor \frac{N-1}{2} \rfloor} \frac{\hat{S}(f_k)}{S(f_k; \hat{\theta})};$$

$S(f_k; \hat{\theta})$  is theoretical SDF depending on  $\hat{\theta}$ ; and either  $\hat{\theta} = [\hat{\phi}, \hat{\sigma}_\epsilon^2]^T$  or  $\hat{\theta} = [\hat{\delta}, \hat{\sigma}_\epsilon^2]^T$

2. cumulative periodogram test statistic:

$$T_2 = \max \left\{ \max_l \left( \frac{l}{\lfloor \frac{N-1}{2} \rfloor - 1} - \mathcal{P}_l \right), \max_l \left( \mathcal{P}_l - \frac{l-1}{\lfloor \frac{N-1}{2} \rfloor - 1} \right) \right\},$$

where  $\mathcal{P}_l$  is the normalized cumulative periodogram for  $\hat{\epsilon}_t$  (likewise for  $\hat{\epsilon}_t$ ):

$$\mathcal{P}_l \equiv \frac{\sum_{k=1}^l \hat{S}_{\hat{\epsilon}_t}(f_k)}{\sum_{k=1}^{\lfloor \frac{N-1}{2} \rfloor} \hat{S}_{\hat{\epsilon}_t}(f_k)}$$

3. Box–Pierce portmanteau test statistic:

$$T_3 = N \sum_{\tau=1}^K \hat{\rho}_{\hat{\epsilon}_t, \tau}^2$$

where  $\rho_{\hat{\epsilon}_t, \tau}$  is estimated ACS for  $\hat{\epsilon}_t$  (likewise for  $\hat{\epsilon}_t$ )

4. Ljung–Box–Pierce portmanteau test statistic:

$$T_4 = N(N+2) \sum_{\tau=1}^K \frac{\hat{\rho}_{\hat{\epsilon}_t, \tau}^2}{N-\tau}$$

## Goodness of Fit Tests: II

- if  $T_j$  ‘too big,’ reject ‘model is adequate’ hypothesis
- can determine what is ‘too big’ under null hypothesis that model is correct
- Tab. 2: model goodness of fit tests for NPI
  - can reject white noise model
  - cannot reject either AR(1) or FD model for NPI (some *very* weak hint that FD is better)
  - similar results obtained for Sitka
- Q: can we really expect to distinguish between AR(1) and FD models given just  $N = 100$  values for NPI?

## AR(1) & FD Model Discrimination

- to address question, consider following experiment
- assume FD model with observed  $\hat{\delta}$  is correct for NPI
- simulate time series of length  $N'$  from FD model
- fit AR(1) model to simulated FD series
- evaluate fitted AR(1) model using each  $T_j$
- repeat above large # of times (2500)
- can estimate probability that  $T_j$  will (correctly) reject null hypothesis that AR(1) model is correct
- gives power of  $T_j$  in saying AR(1) model is incorrect
- repeat above for variety of sample sizes  $N'$
- can repeat all of the above with roles of FD & AR(1) processes interchanged
- Fig. 4: power of various test statistics vs.  $N'$ 
  - in best case, need  $N' \approx 500$  to have 50% chance of discriminating between models
  - portmanteau tests to be preferred over  $T_1$  and  $T_2$

## AR(1) & FD Model Implications: I

- no statistical reason to prefer AR(1) over FD model for NPI (or *vice versa*)
- both AR(1) & FD models depend on 3 parameters & hence are equally simple (i.e., cannot appeal to Occram's razor here)
- even though both describe NPI equally well, models can have potentially important implications if one is selected in favor of the other
- as example, will consider extent to which models support notion of 'regimes' in NPI
- regime is time interval over which series is essentially either  $>$  or  $<$  its long term average value
- Fig. 1: plot of NPI and 5 year running mean
  - data for 1901–23 are essentially  $>$  sample mean (exceptions are 1905 & 1919)
  - called positive regime with duration of 23 years
  - clearly identified in 5 year running mean
  - latter is essentially  $<$  sample mean for 1924–46 (but not strictly so)

## AR(1) & FD Model Implications: II

- Q: how do fitted AR(1) & FD models impact distribution of regime sizes?
- to address question, consider following experiment
- generate deviate  $\tilde{\delta}$  from normal distribution with mean  $\hat{\delta}$  from NPI and variance  $\frac{6}{\pi^2 N} = \frac{6}{\pi^2 100}$
- assume FD model with  $\tilde{\delta}$  is correct for NPI
- simulate time series of length 1024 from FD model
- tabulate sizes of observed regimes in
  1. simulated series
  2. five year running mean of series
- repeat above 1000 times
- also repeat using fitted AR(1) model for NPI
- Fig. 5: plots of empirically determined probabilities of regime sizes being  $\geq$  specified sizes
- regime size  $\geq 23$  is 4 times more likely under FD model than under AR(1)
- similarly, regime size  $\geq 35$  is 10 times more likely

## Long Memory Model Interpretation

- for both NPI & Sitka, fitted FD model has  $\hat{\delta} \approx 0.2$
- allowable range of  $\delta$  for stationary FD models with long memory is  $0 < \delta < \frac{1}{2}$
- as  $\delta \rightarrow 0$ , FD process  $\rightarrow$  white noise ('no memory')
- as  $\delta \rightarrow \frac{1}{2}$ , FD process has strong long memory effect
- Fig. 6: gives some idea how to interpret  $\delta$ 
  1.  $\delta = 0.02$  is lower end of 95% CI for  $\delta$  in NPI case
  2.  $\delta = 0.17$  is estimated value for NPI
  3.  $\delta = 0.32$  is upper end of 95% CI
  4.  $\delta = 0.45$  corresponds to strong LM effect
- simulated series in a given column constructed using same white noise sequences
- as  $\delta$  increases, average regime sizes increase
- increase not linear in  $\delta$ : cases  $\delta = 0.32$  &  $0.17$  similar & substantially different from  $\delta = 0.02$  case
- can thus interpret  $\delta$  as indicator of how much regime-like structure there is in a time series

## Conclusions

- AR(1) & FD models equally adequate for time series considered here (NPI & Sitka)
- cannot realistically hope to distinguish between AR(1) & FD processes given available sample sizes
- both models include white noise as special case (both lead to rejection of hypothesis of white noise)
- AR(1) model has rapid drop off of ACVS
- FD model has long tail of small positive correlations
- loose physical considerations might favor FD model (aggregation of first order differential equations)
- FD model more supportive of regime-like behavior than AR(1)
- can use  $\delta$  as indicator of regime-like behavior
- for NPI & Sitka, estimated  $\delta$  compatible with notion of regimes, but neither series has strong long memory